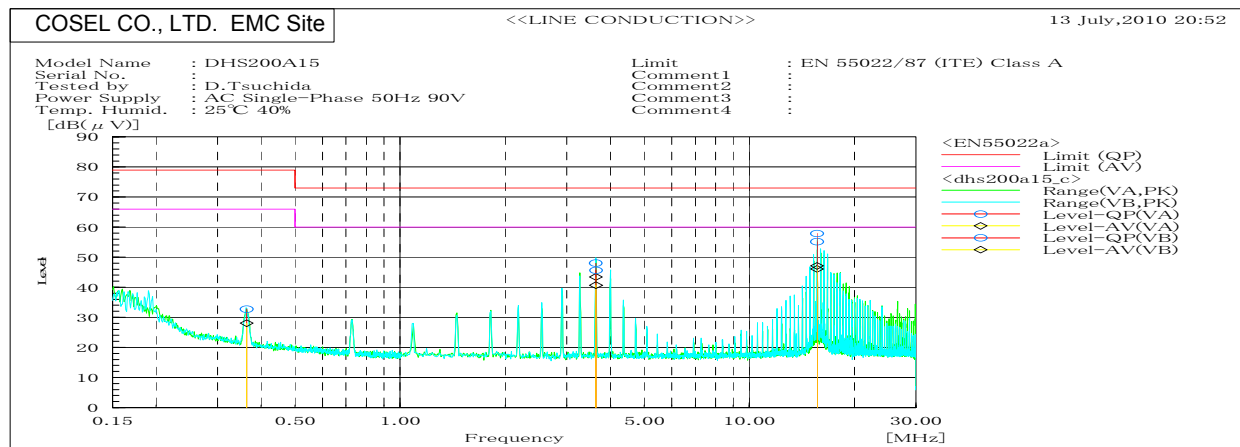
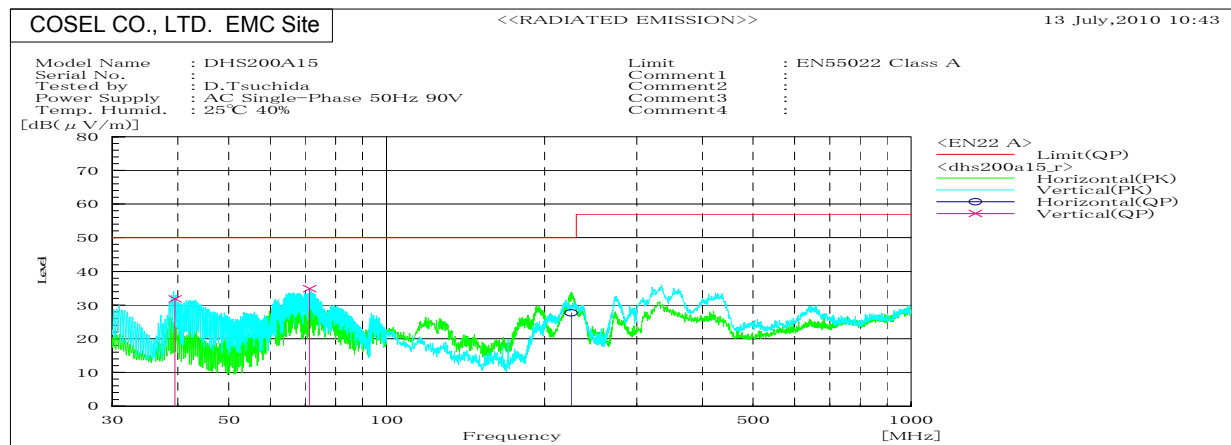


DATA SHEET		Date	10-Aug-10
Model	DHS200A15	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	D.Tsuchida



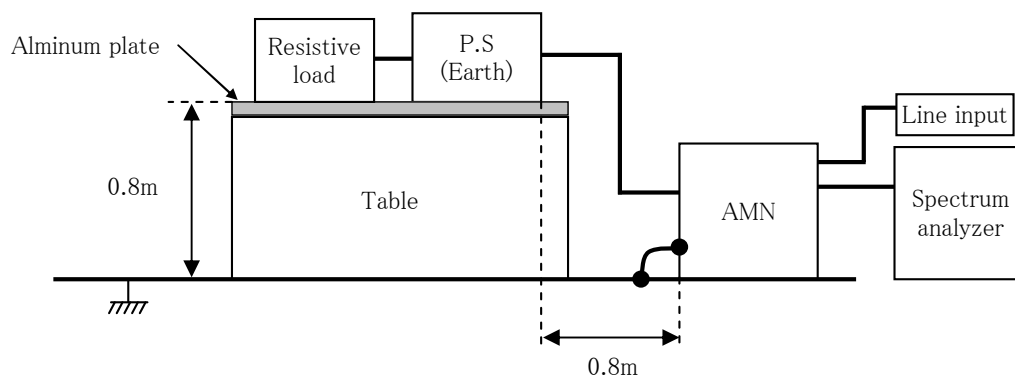
Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.36369		VB	22.7	18.1	10	32.7	28.1	79	66	46.3	37.9	Pass	
3.63934		VB	35.4	30.5	10.2	45.6	40.7	73	60	27.4	19.3	Pass	
3.6343		VA	37.8	33.3	10.2	48	43.5	73	60	25	16.5	Pass	
15.6222		VB	47.3	36.5	10.6	57.9	47.1	73	60	15.1	12.9	Pass	
15.6189		VA	44.6	35.5	10.6	55.2	46.1	73	60	17.8	13.9	Pass	



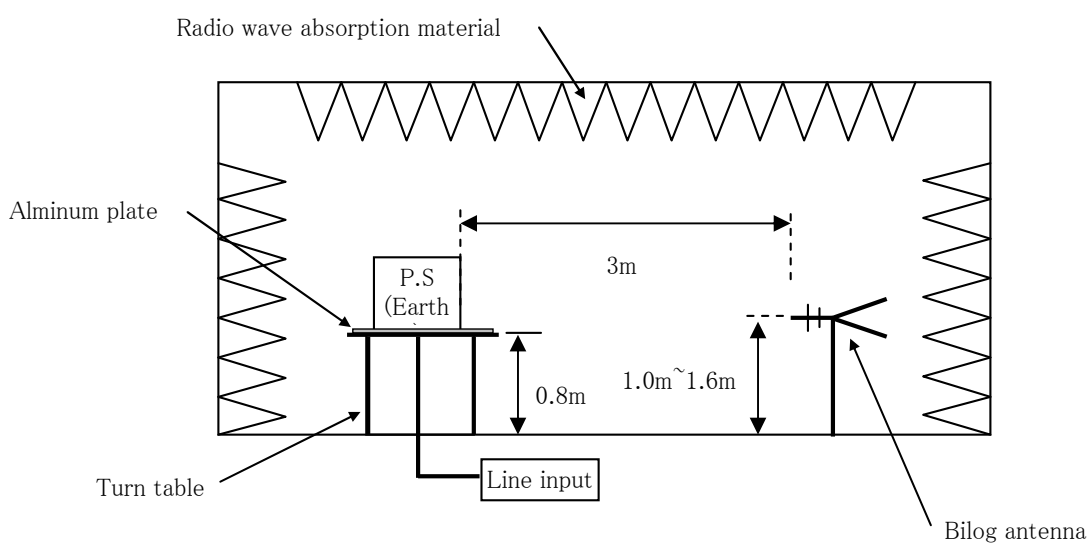
Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV						
39.484	V	Stable	50.7		-18.8	31.9		50	18.1	Pass	105	85	
71.341	V	Stable	60.1		-25.2	34.9		50	15.1	Pass	112	112	
224.924	H	Stable	48.9		-21.2	27.7		50	22.3	Pass	126	47	

DATA SHEET		Date	10-Aug-10
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	D.Tsuchida

1. Line conduction



2. Radiated emission

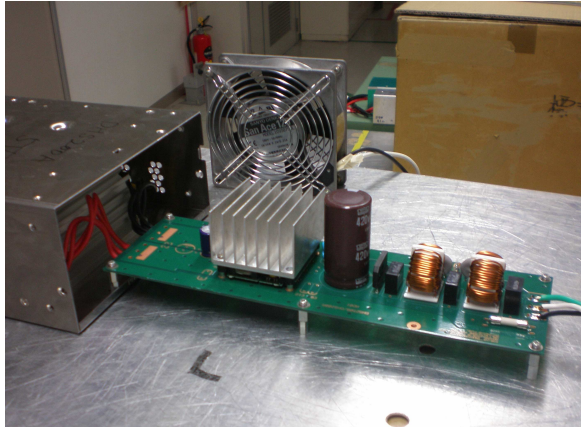


Test: EMI

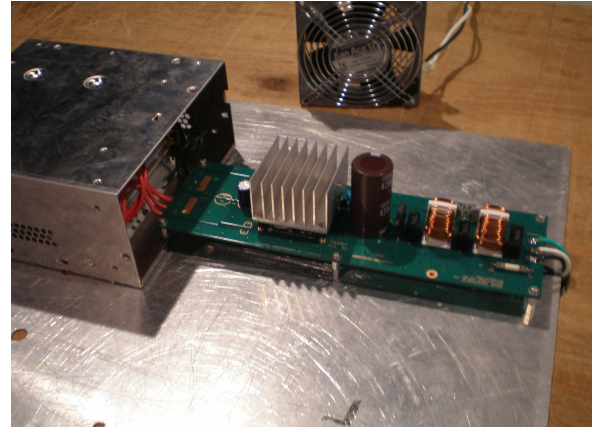
Model Name:DHS200A Series

○ Photographs of Test Set-Up

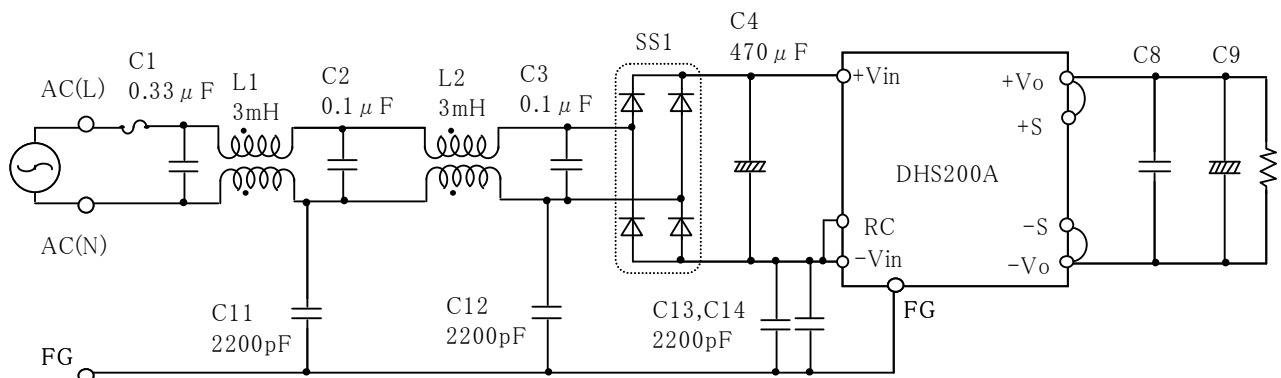
LINE CONDUCTION



RADIATED EMISSION



○ Test circuit



L1,L2 : SC-10-300(NEC TOKIN)

SS1 : D10XB60(SINDENGEN)

C8 : DHS200A05	10 μ F	C9 : DHS200A05	2200 μ F
DHS200A12	10 μ F	DHS200A12	1000 μ F
DHS200A15	10 μ F	DHS200A15	1000 μ F
DHS200A24	4.7 μ F	DHS200A24	470 μ F